

<b>Notice of References Cited</b>	Application/Control No. 10/634,592	Applicant(s)/Patent Under Reexamination KOZAWA ET AL.	
	Examiner Laura S. Weiner	Art Unit 1745	Page 1 of 1

**U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	A	US-6,475,676	11-2002	Sawai, Ken	429/248
	B	US-			
	C	US-			
	D	US-			
	E	US-			
	F	US-			
	G	US-			
	H	US-			
	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

**FOREIGN PATENT DOCUMENTS**

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	N	JP 2001-313064	11-2001	Japan	Ikeda et al.	
	O				Patent and abstract	
	P					
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	S					
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**NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
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